

<b>Notice of References Cited</b>	Application/Control No. 10/572,952		Applicant(s)/Patent Under Reexamination INOUE, SHUICHI	
	Examiner William H. Mayo III		Art Unit 2831	Page 1 of 3

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<b>Notice of References Cited</b>	Application/Control No. 10/572,952		Applicant(s)/Patent Under Reexamination INOUE, SHUICHI	
	Examiner William H. Mayo III		Art Unit 2831	Page 2 of 3

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<b>Notice of References Cited</b>	Application/Control No. 10/572,952	Applicant(s)/Patent Under Reexamination INOUE, SHUICHI	
	Examiner William H. Mayo III	Art Unit 2831	Page 3 of 3

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